



**Experiment title:**  
Is there in glasses a characteristic correlation length for the elasticity?

**Experiment number:**  
SC-4955

<b>Beamline:</b> ID18	<b>Date of experiment:</b> from: 01/10/2018 to: 08/10/2018	<b>Date of report:</b> 17/03/2020
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## Report

Glasses at low temperature (below 10 K) display thermal and vibrational properties markedly different from those of crystals [1]. In glasses, long-wavelength phonons (~GHz) are considerably more damped because of the presence of disorder in the elastic constants. In particular it has been recently argued that this elastic disorder in glasses should be characterized by **long-range correlations** [1].

These correlations are expected to give rise to a logarithmic correction to the **Rayleigh** ( $\Gamma_p \propto E^4$ ) term expected in case of scattering from uncorrelated heterogeneous elastic disorder [2]. Directly accessing the relevant frequency range to test this hypothesis is at present impossible on bulk samples. An alternative route is to study the low frequency (< 1 meV) tail of the vibrational density of states (DOS), which is directly related to sound attenuation [2].

The aim of this experiment was to measure the low-energy part of the DOS of the prototypical glass-former SiO<sub>2</sub> exploiting the very high energy resolution of the Hard X-ray spectrograph

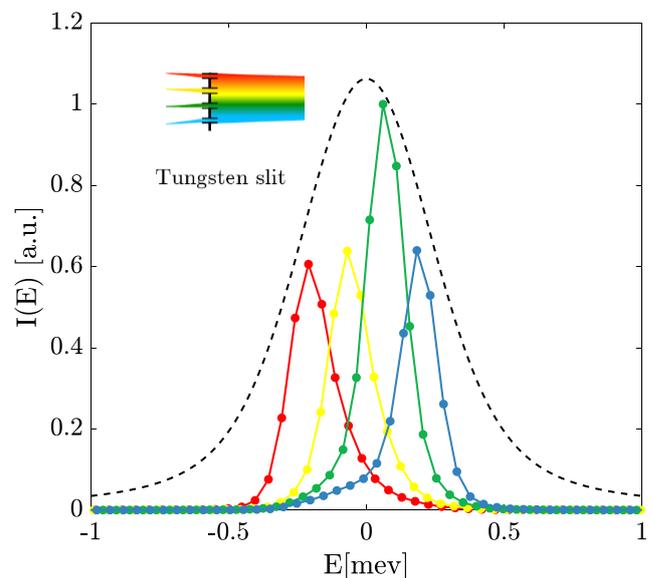


Figure 1: Instrumental response of the spectrograph: from the dispersed beam four “colors” are selected using a tungsten slit.

recently developed at the beamline ID18 [3] combined with high resolution inelastic X-ray scattering with nuclear resonant analysis (NRAIXS) [4]. More in detail, the employed spectrograph is able to disperse photons at different energies into distinct spatial locations. Using a tungsten slit we could select four different beams, each of them with an energy resolution of roughly  $150 \mu\text{eV}$  (FWHM, see Fig. 1), which were then used to ‘perform’ 4 inelastic scattering experiments in parallel. In this way the efficiency of the measurements is increased as the total energy spectrum is obtained from the average of the four ones collected exploiting the different “colors” emerging from the spectrograph. The inelastically scattered intensity was then analysed using an  $\alpha\text{-}^{57}\text{Fe}$  foil, achieving a total bandpass in detection of  $0.5 \mu\text{eV}$  [4]. The overall energy resolution for the measured inelastic spectra was therefore fixed by that of the incident beam. The inelastic spectra were measured integrating the scattered radiation over a large range of scattering vectors  $q = 1.4 - 14 \text{ \AA}^{-1}$  to ensure the validity of the incoherent approximation [5] and an appropriate

integration of the vibrational states: both are required for the extraction of the DOS. The vibrational dynamics of  $\text{SiO}_2$  was investigated at two different temperatures:  $T=150$  and  $300 \text{ K}$ . Fig. 2 shows the inelastic X-ray scattering spectrum of  $\text{SiO}_2$  at  $300 \text{ K}$  (blue curve), along with the total instrumental response. The extracted spectra are characterized by an energy resolution of  $170 \mu\text{eV}$ . The data analysis process is basically completed and we succeeded to extract the

DOS of  $\text{SiO}_2$  down to energies of  $300 \mu\text{eV}$  at both the investigated temperatures. We are now starting to prepare a paper to present the obtained results [6].

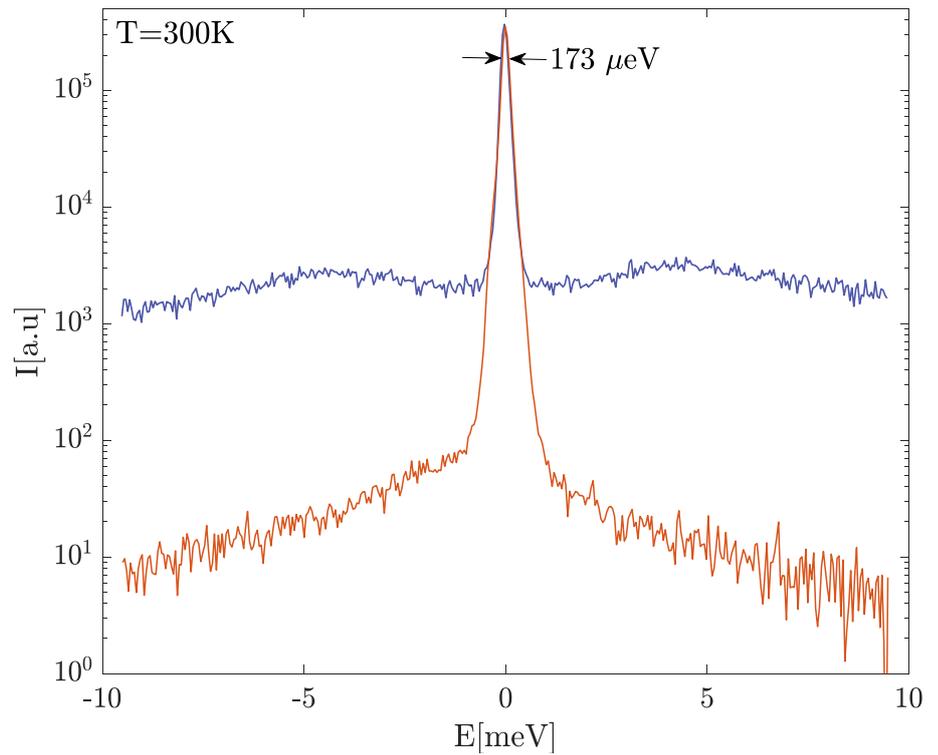


Figure 2: Energy spectrum of the inelastic X-ray scattering from  $\text{SiO}_2$  (blue line) and instrumental response (orange line).

## References

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